## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | TATSUKAWA ET AL. | Examiner | Art Unit | Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,194,248 B1	02-2001	Amaya et al.	438/110
*	В	US-2002/0144765 A1	10-2002	Tatsukawa et al.	156/89.12
*	С	US-2004/0084131 A1	05-2004	Konoue et al.	156/089.11
*	D	US-6,169,470 b1	01-2001	Ibata et al.	336/83
*	Е	US-6,229,425 B1	05-2001	Kobayashi, Hirofumi	336/200
*	F	US-2002/0008606 A1	01-2002	Okuyama et al.	336/200
*	G	US-6,115,264	09-2000	Nosaka, Koji	361/821
*	Н	US-5,250,923	10-1993	Ushiro et al.	336/83
	ı	US-			
	J	US-			
	K	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
6	R					
	s					
	I				100	

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	x	

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